

# **FPGA Emulation of Laser Attacks Against Secure Deep Submicron Integrated Circuits**

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# Summary

Register Transfer - Level Laser Fault Injection Modeling and the implementation of a Simulation – Emulation Platform, for the Evaluation of Countermeasures for **Cryptographic ASICs** 



- Laser Fault Injection (LFI) enables attackers to perform fault injection in Cryptographic circuits characterized by: High precision locality
  - Accurate timing
  - High occurrence probability of faults
- Laser Fault injection Modeling in the RT-Level provides evaluation of Security ASICs early in the design flow
  - Avoidance of costly feedback runs
  - Fault injection close to the design process
  - Efficient Design and evaluation of countermeasures



## **Fault Modeling**

#### **Classical approaches**

- Single Bit-flipping
- Originates from SEU resulting from high energy particles with the assumption that the deposited charge affects a single flip-flop • Time consuming analysis for Multiple Bit-Flipping, even for circuits of moderate complexity, leads to the simplification of the models. Laser Fault Injection is approached with classical fault models, which are not well adapted to new technology IC sizes, and generic simulator or emulator architectures

# **Fault Simulator & Emulator**

### **Emulation based fault injection**

Utilization of powerful emulation techniques in FPGA platforms



#### **Our Approach**

Reduction of the gap between the characteristics of the laser beam and classical fault models (SEU, SET) for recent semiconductor technology nodes (28nm) **Testing and Refinement of the Model by evaluation with a** gate-level fault simulator developed within the project

- > Run Time Dynamic FPGA Reconfiguration
- Instrumentation with RTL code mutation
- Goals
  - > Observability maximization
  - Fault Injection Campaign duration reduction

Thus making feasible the application of a realistic laser fault model to the ASIC under analysis including the accuracy and complexity it requires



- Validation of the model by performing fault injections on state of the art cryptographic circuits
  - > Advantages : Early in, and close to, the design flow, faster than a gate level model
  - > Challenges : Maintain the necessary accuracy besides the lacking of synthesis and placement information

- The design and integration of efficient countermeasures in a cryptographic circuit against an attack depends highly on the means available to validate them early in the design stage
- Therefore the RTL analysis tools will provide the means to efficiently expose vulnerabilities of security circuits, and at the same time assist the implementation of both defensive and preventive mechanisms

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